		Application/Control No.		Applicant(s)/Pat	Applicant(s)/Patent under Reexamination	ion
Issue Classification	sification	10650030		EVANICKY ET AL.	نـ	
		Examiner		Art Unit		
		Nguyen, Kevin M		2629		
	ORIGINAL		INTE	RNATIONAL	INTERNATIONAL CLASSIFICATION	Z
CLASS		SUBCLASS	СГАІМЕР	ED	NON-CLAIMED	MMED
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)	CROSS REFERENCE(S)	VCE(S)	-			
CLASS	SUBCLASS (ONE SUBCLASS	JBCLASS PER BLOCK)				
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Kevin M. Nguyen Kerin M. Haylu 6/28/2006 (Assistant Examiner) (Date)	1. Hour 6128/2006 (Date)		RICHARD L'AEDDE		Total Claims Allowed: 20	Allowed:
While EEE (Legal Instruments Examiner)	er 7/e/06 (Date)	(Primary Examiner)	Supervisory patent examiner Technology (bate)	1/100	O.G. Print Claim(s) 1	O.G. Print Figure 9

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